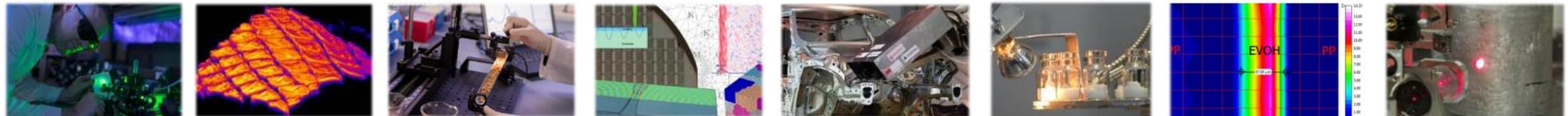


# Anwendungen von Laserultraschall als zerstörungs- und kontaktfreie Methode in der Dünnschichtcharakterisierung

Dr. Mike Hettich

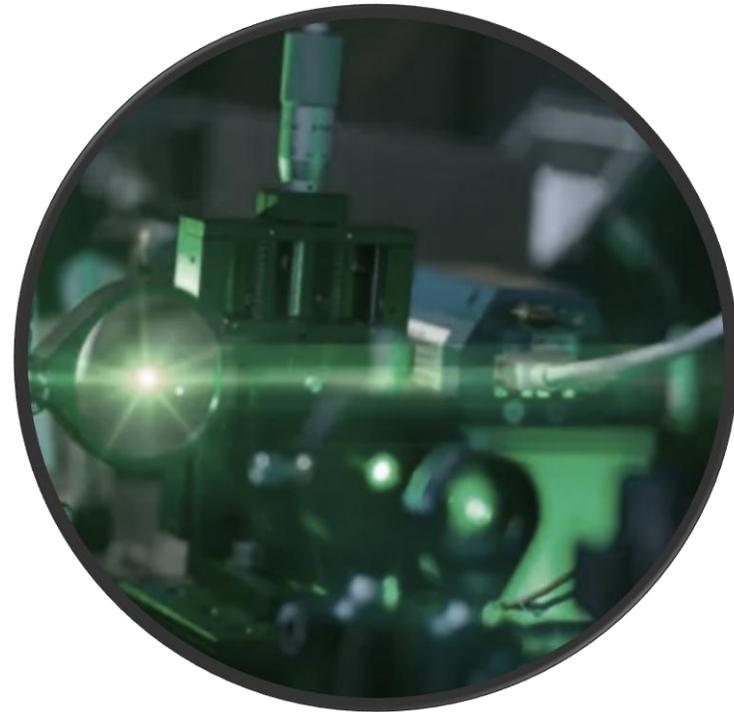
Lead Scientist Acoustics, RECENDT GmbH

EFDS Workshop Linz: Dünnschichtcharakterisierung, 10-11 November 2025

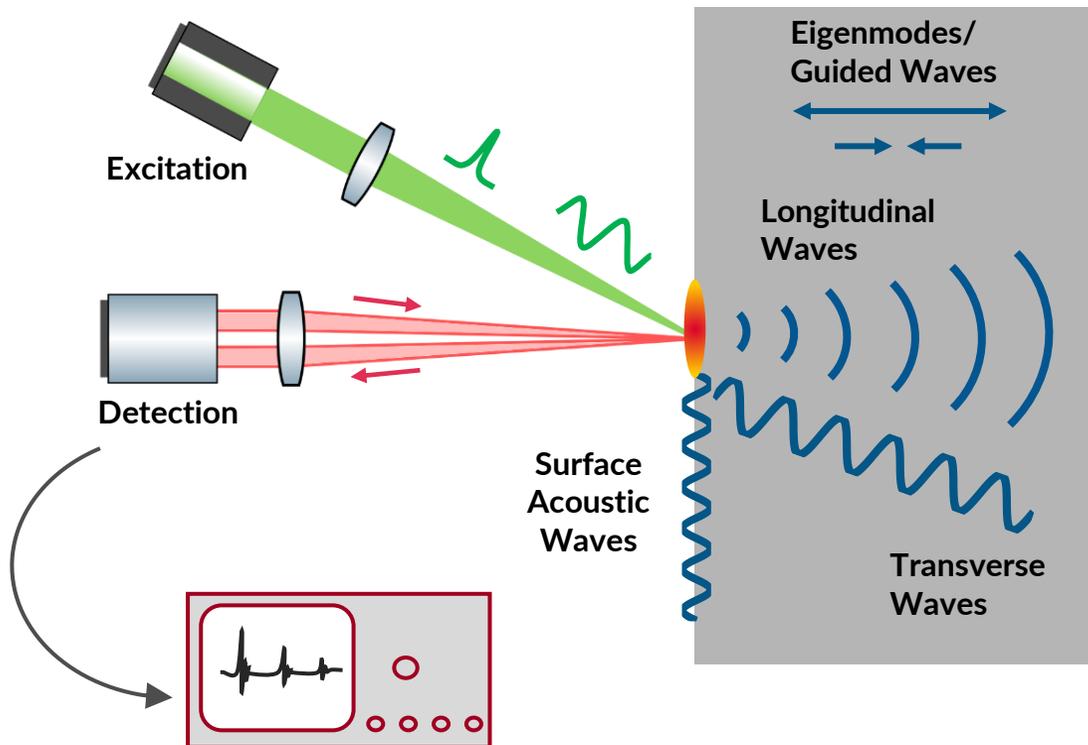


# Laser Ultrasonics

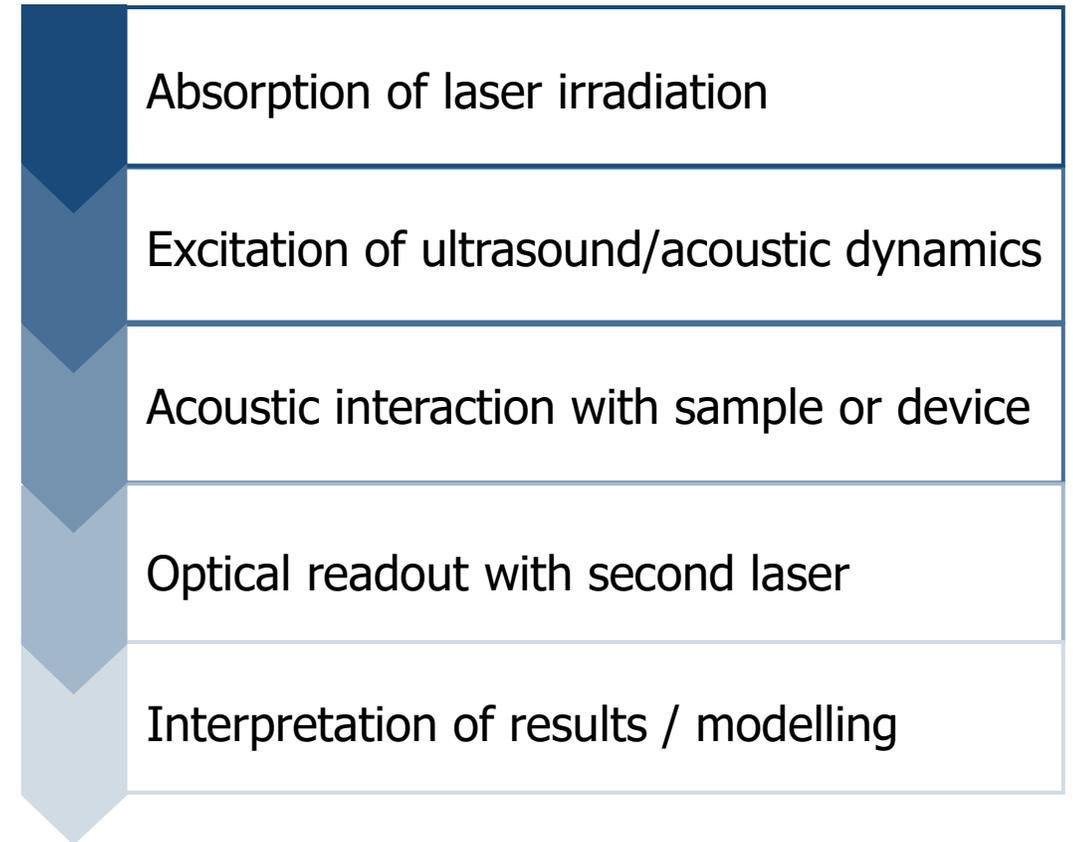
One concept - many applications



All optical excitation and readout of acoustic dynamics



Main steps in LUS methodology



## Resonances/Guided Waves

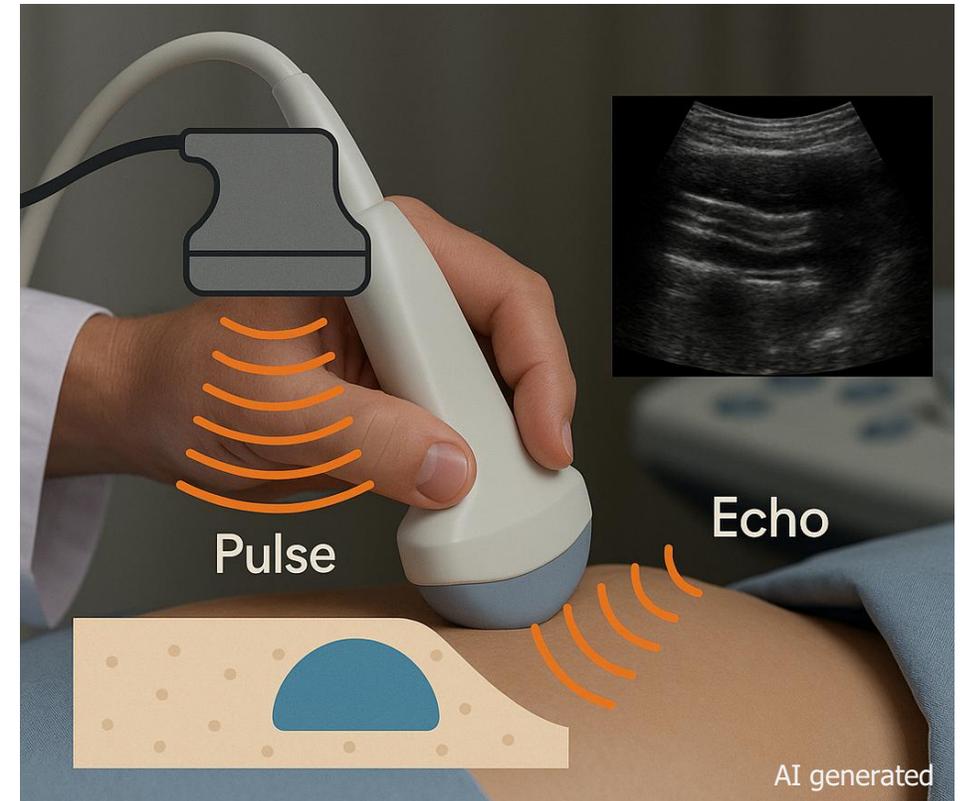


Clapper



Laser excitation

## Pulse-Echo



Meters  
Tens of centimeters

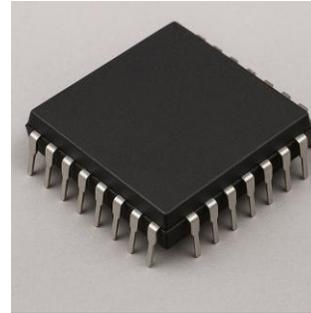
Centimeters  
Millimeters

Micrometers  
Nanometers

Steel industry



Packaging  
Welding  
Wafer-Bonding  
Microstructure

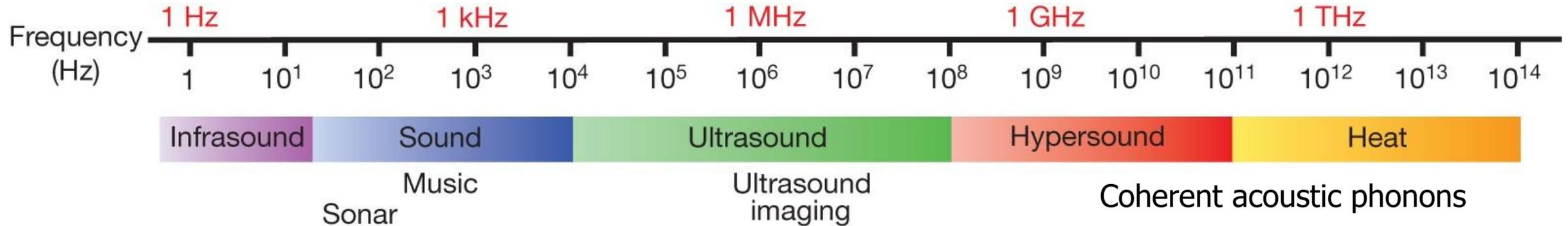


Thin films/Multilayers  
Micro-/Nanostructures

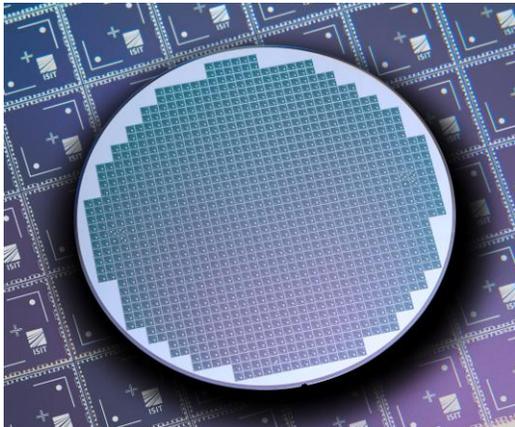
3-30 nm  
0.7-14 nm  
Substrate



Laser ultrasonics covers a broad frequency range



- ✓ All-optical excitation and detection
- ✓ Non-contact
- ✓ Non-destructive



Source:  
<https://www.isit.fraunhofer.de/de/mikro-fertigungsverfahren/module-services/testwafer-substrate/silizium-wafer.html>

- ✓ Lateral resolution sub- $\mu\text{m}$  possible
- ✓ Axial resolution down to single nm
- ✓ In-situ/Inline capability
- ✓ Harsh environments



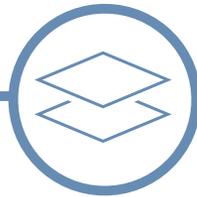
# Laser Ultrasonics



## Structural/Elastic Characterization

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Elastic/ Viscoelastic Properties  
Adhesion  
Acoustic Damping  
Doping Profiles  
Layer Thickness/ Periodicity  
Internal/Residual Stresses  
...



## Defect Detection

---

Delamination  
Voids  
Cracks  
...



## Materials/Systems

---

Metals	
Semiconductors	Multilayers
Polymers	
Oxides	
Shape Memory Alloys	Superlattices (E.g. Bragg Mirrors)
Makro- Nanosystems	
Thin films	

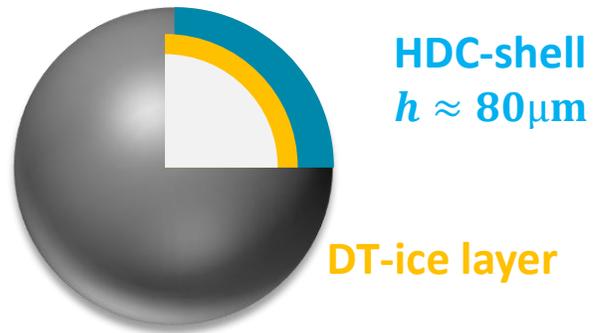
# Thin Film Metrology

Examples



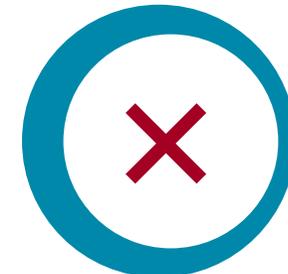
# Nuclear Fusion Target Inspection

Inertial  
Confinement  
Fusion Target



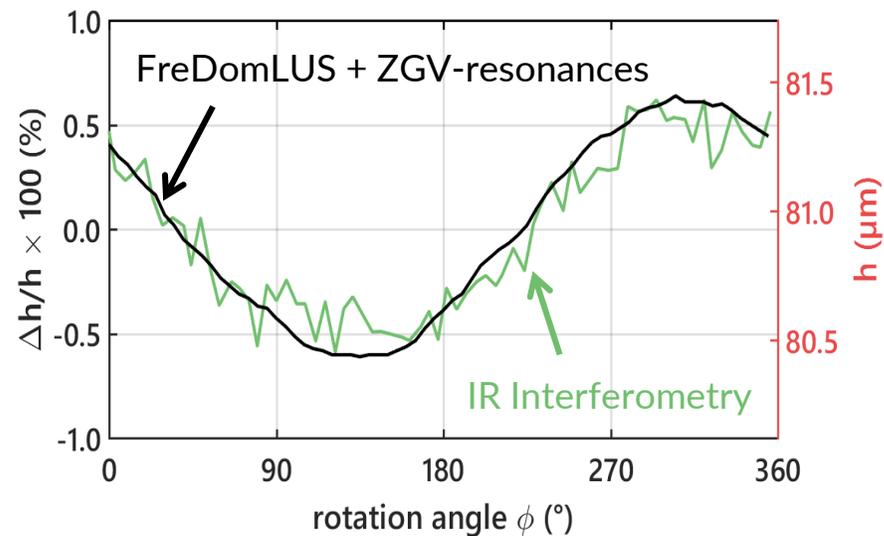
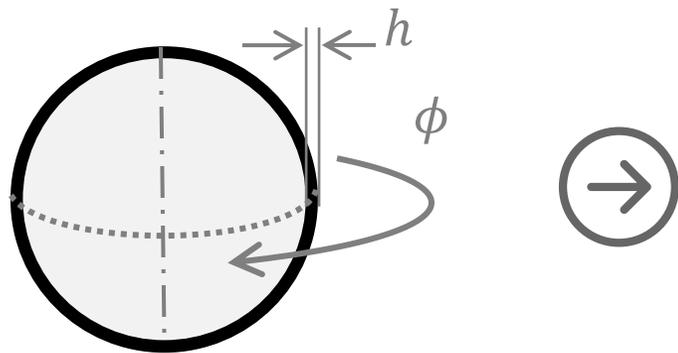
ISSUE

Non-uniform shell thickness  
Optical testing not possible



Inefficient or no nuclear fusion

SOLUTION: Zero-Group Velocity Modes as local thickness measurement



Currently integration into test devices

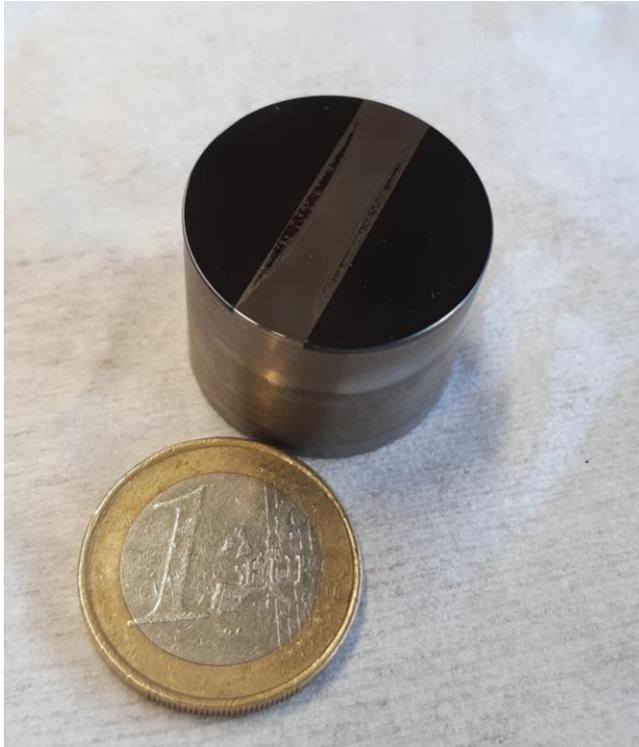
Austrian press articles

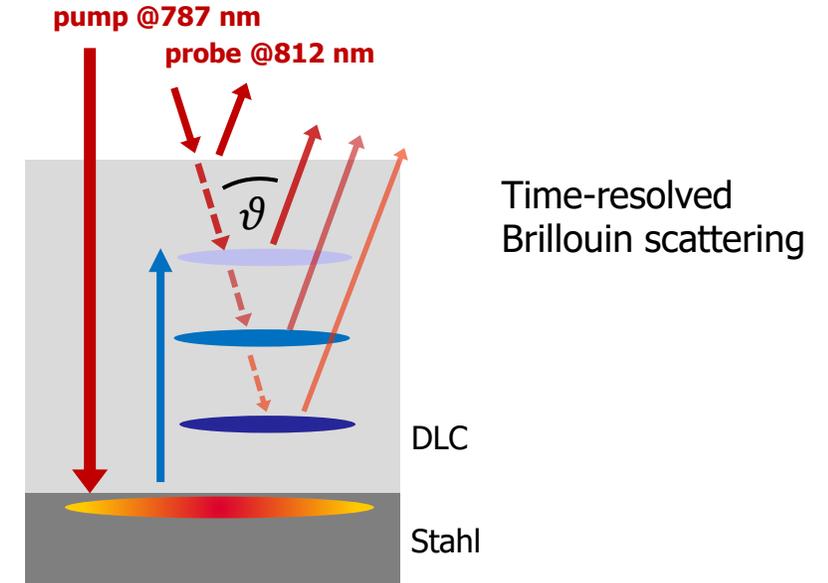
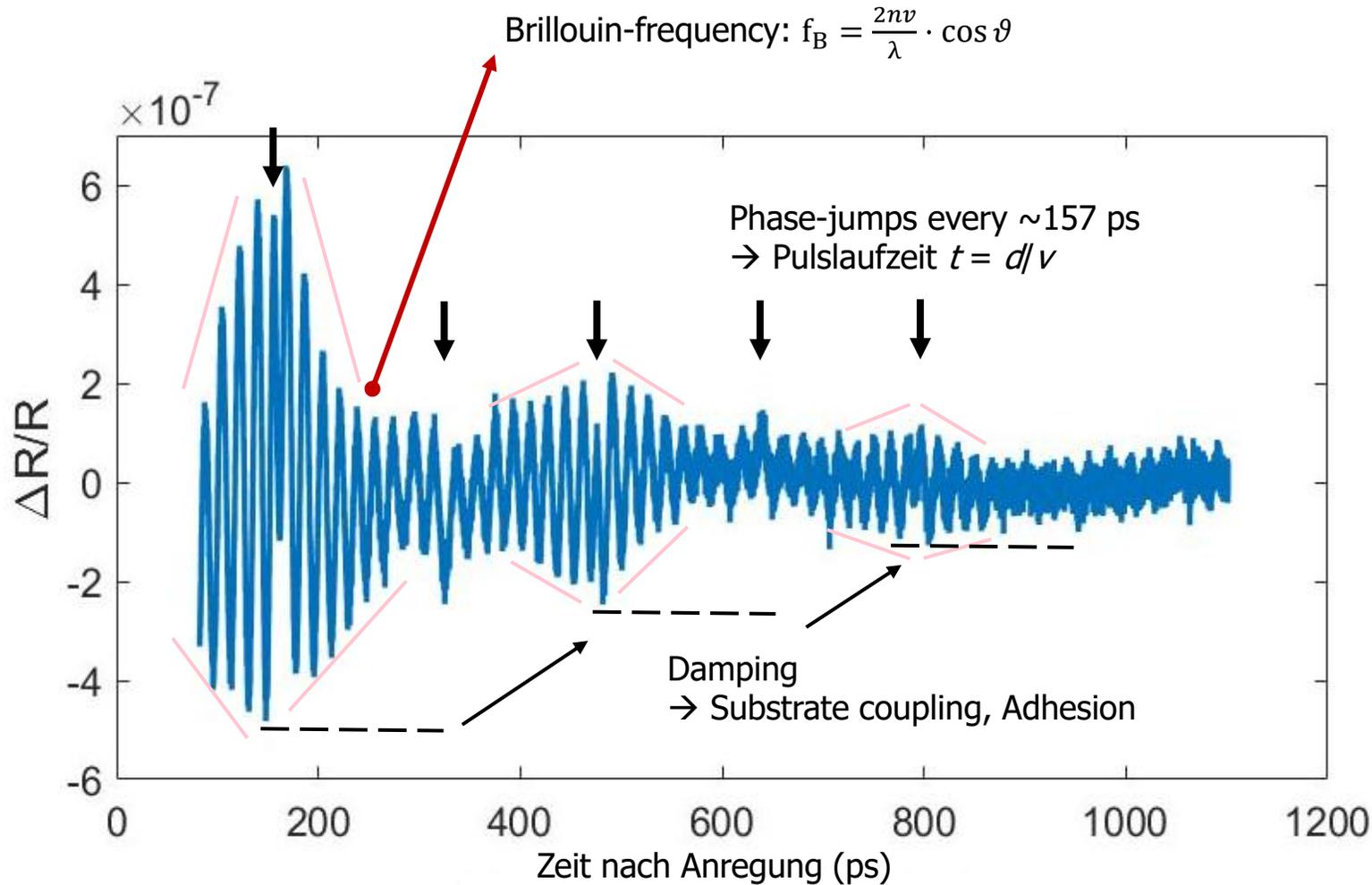


Yan, Guqi et.al.  
*Journal of Physics: Conference Series*,  
Vol. 2966, No. 1, online 31.03.2025 (7th  
Int. Symposium on Laser Ultrasonics and  
Advanced Sensing (LU2024), Oct. 2024,  
Nanjing, China), IOP Publishing, DOI:  
[10.1088/1742-6596/2966/1/012007](https://doi.org/10.1088/1742-6596/2966/1/012007)

# Micronlayers and 3D-structures

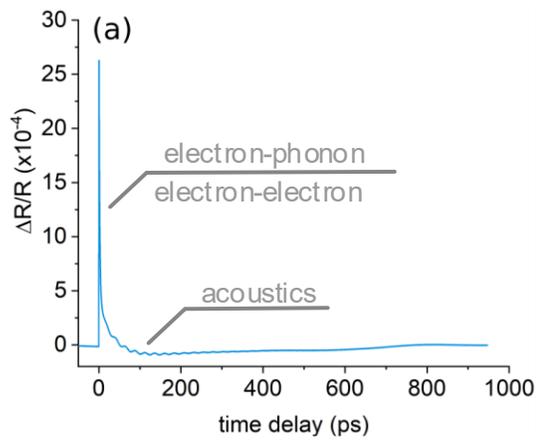
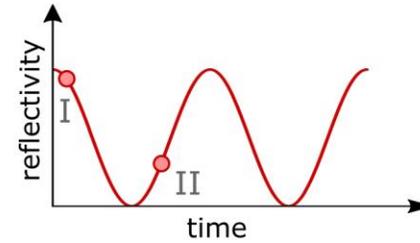
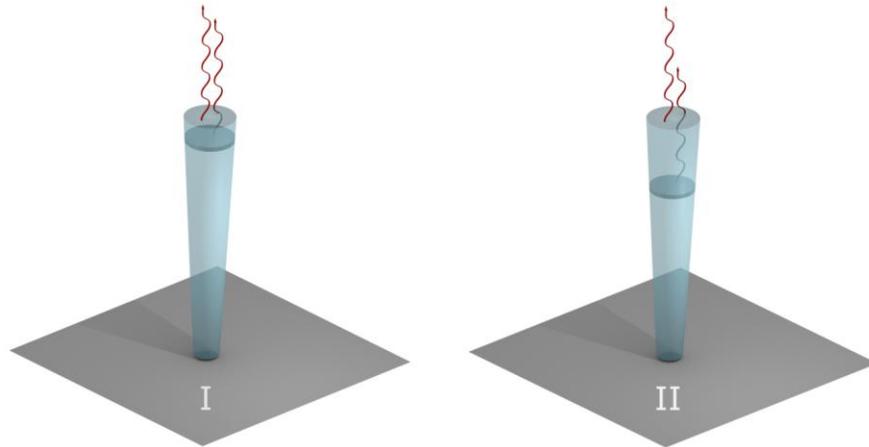
# Diamond Like Carbon



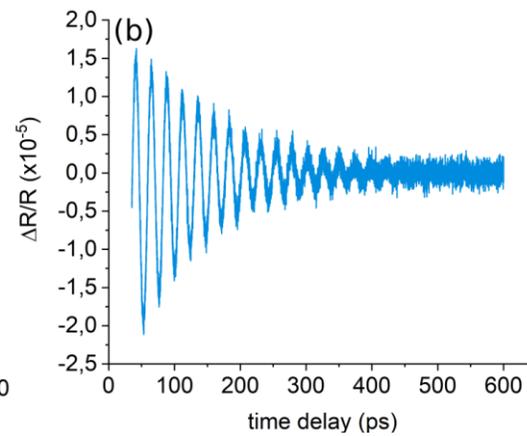


- Optical absorption and pulse generation in steel substrate
- Phase jumps in signal when pulse traverses interface or surface
- Interface sensitivity through acoustic reflection coefficient

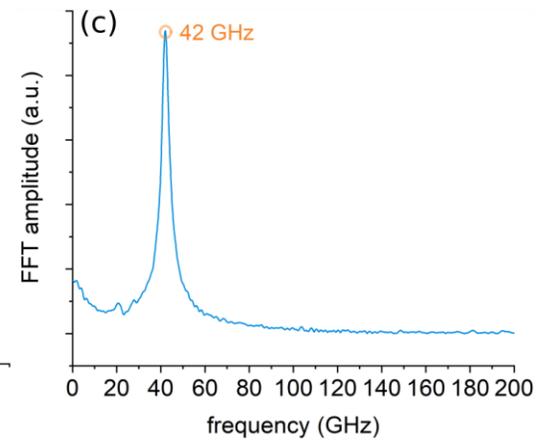
# Looking into Micromechanical Resonators



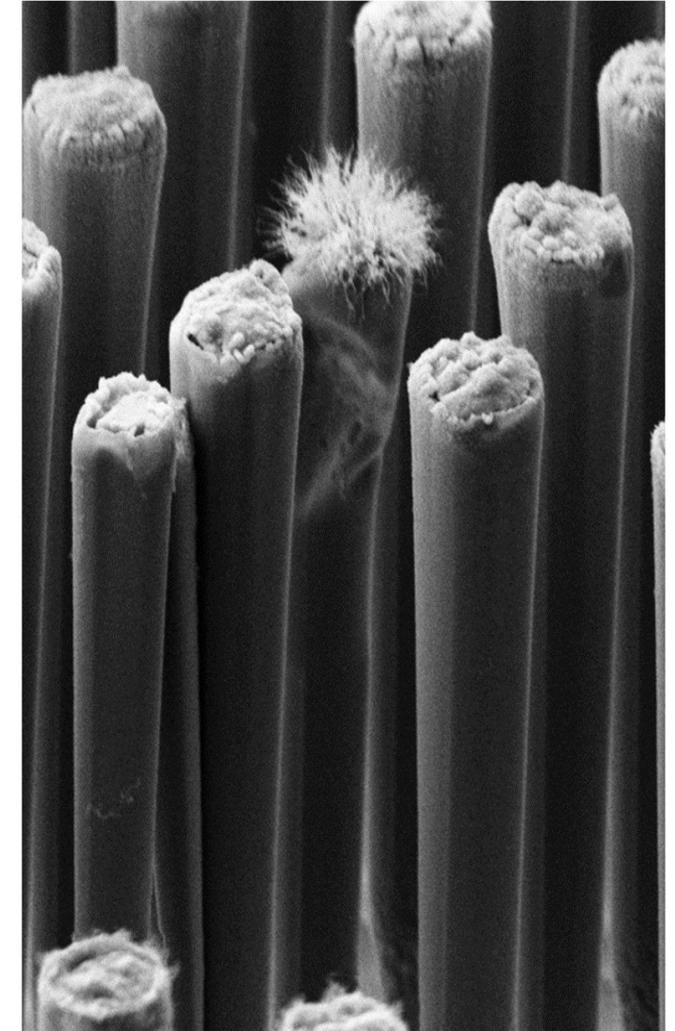
Detected signal on pillar



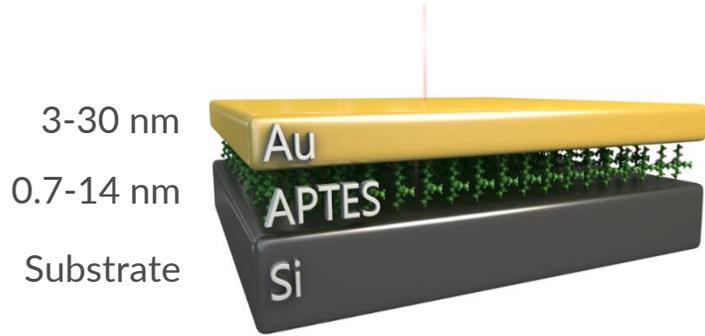
→ Acoustic component



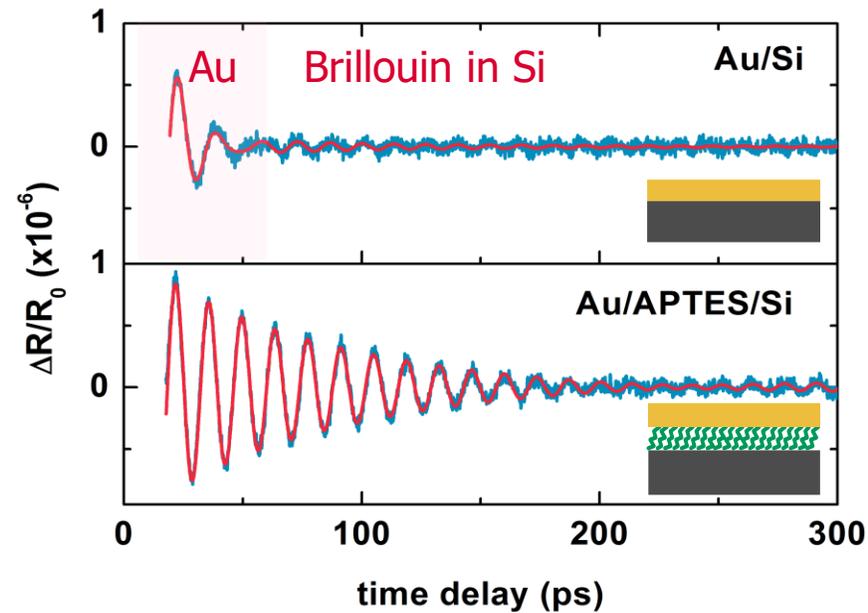
→ Frequency spectrum



Nanolayers



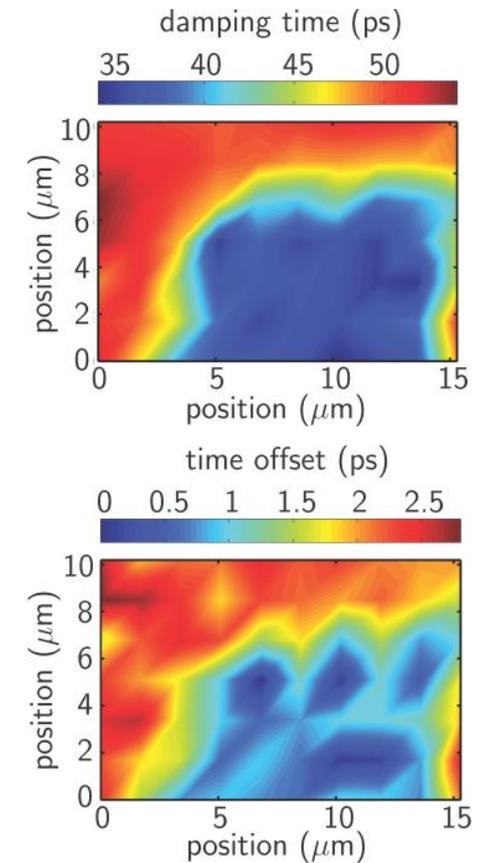
## Acoustic Eigenmodes and Lifetime



Structuring the APTES layer



## Subsurface Imaging

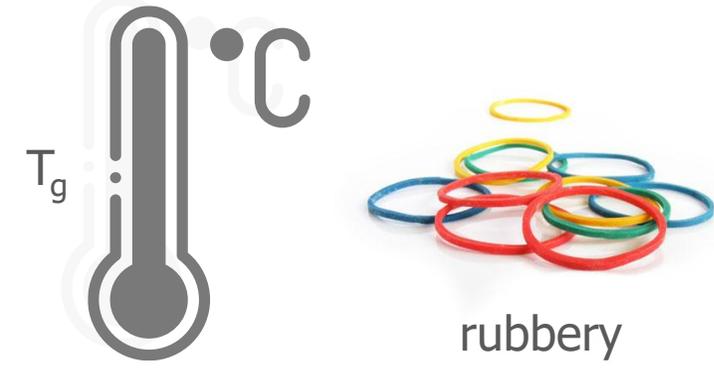
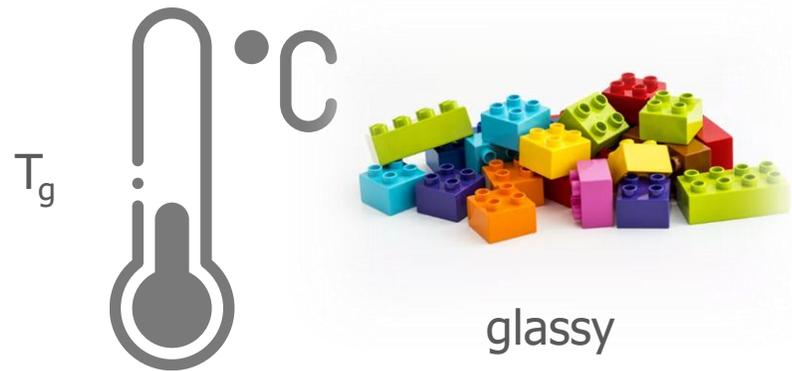


M. Hettich et al., *Appl. Phys. Lett.* **98**, 261908 (2011)

M. Hettich et al., *Appl. Phys. Lett.* **101**, 191606 (2012)

M. Hettich et al., *Scientific Reports* **6**, 33471 (2016)

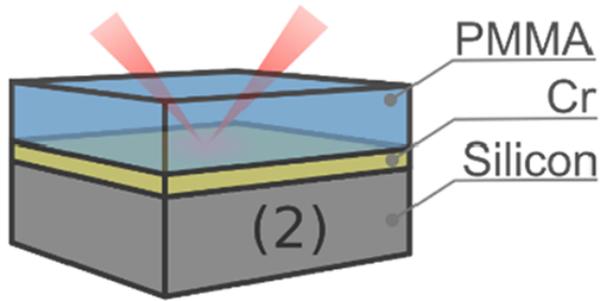
# Ultrathin Polymers – Thickness and Glass Transition



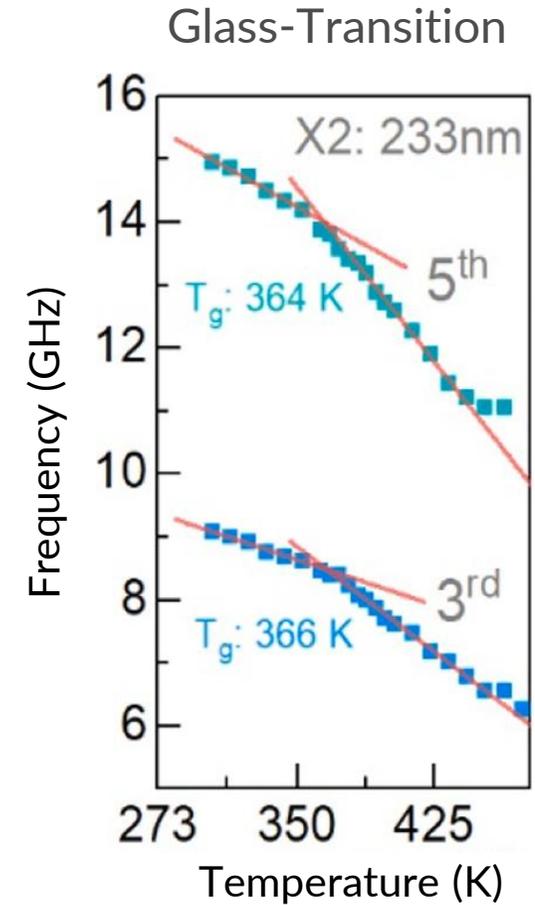
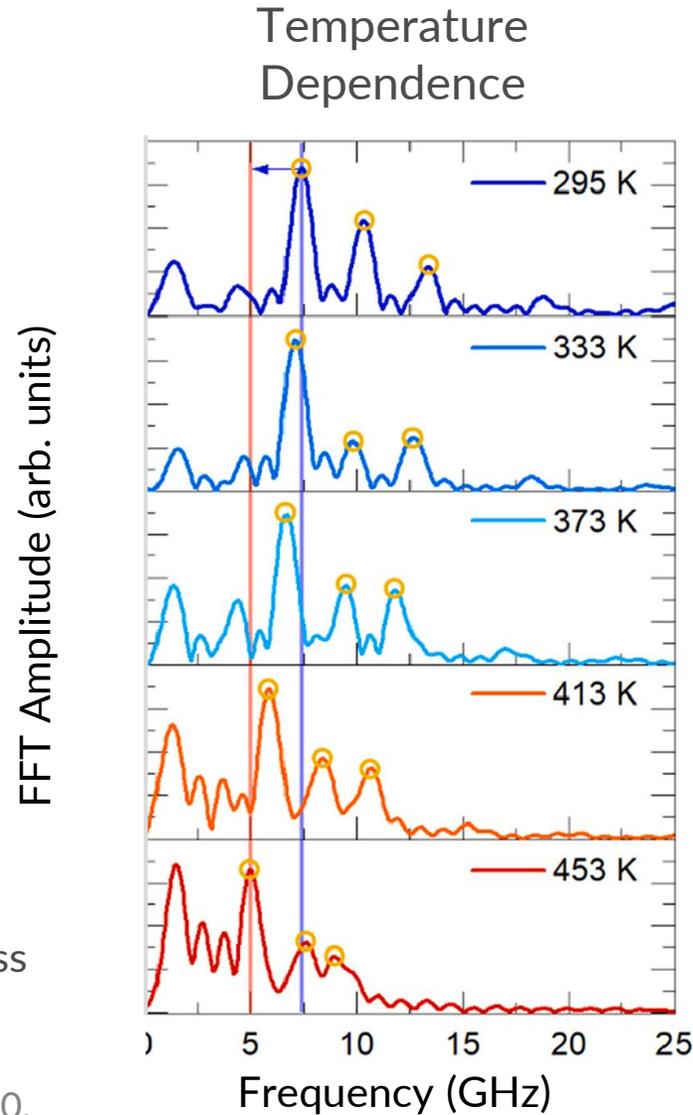


Source: <https://external-content.duckduckgo.com/iu/?u=https%3A%2F%2Ffruggedstandard.com%2Fwp-content%2Fuploads%2F2018%2F11%2Fmid-shot-man-charming-smile-ironing-how-to-iron-a-dress-shirt-ss-FEATURE-.jpg&f=1&nofb=1&ipt=36aaf72d47a8646fe7efea1dacd3e1a023c552e6bd29ce4c1738df64b68930cb>

# Ultrathin Polymers – Thickness and Glass Transition



PMMA-  
Eigenmodes



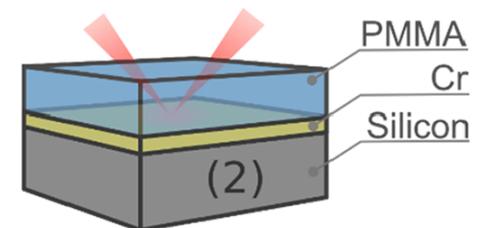
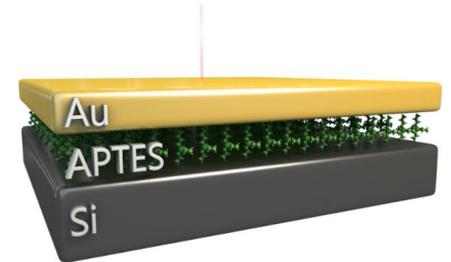
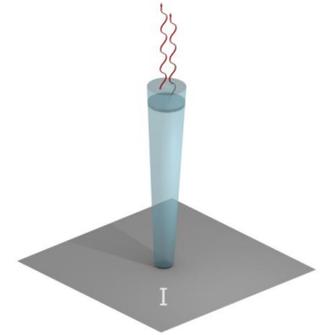
Glass-transition-temperature and thickness measurement in 30-500nm PMMA films

Brick, Delia, et al., *Ultrasonics* **119** (2022): 106630.

Take Home Message

# Laser Ultrasonics - Picosecond Ultrasonics

- A powerful tool for non-destructive and non-contact metrology of thin films, nano- und microstructures, nanoparticles
- Subsurface information accessible with optical lateral resolution down to the sub- $\mu\text{m}$  regime and nm- axial resolution
- Interface sensitive, Adhesion, Film thickness, Doping
- Can in principle be applied during film growth (not demonstrated yet)





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Questions?

